

EMC For Functional Safety

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What is “Functional Safety”

- The correct functioning of an electrical or electronic technology device that provides one or more functions having a direct impact on safety
- Errors or malfunctions could have implications for safety where appropriate EMC engineering is required to control safety risks
- All electrical or electronic technology devices are prone to errors or malfunctions due to EMI

Why is “Functional Safety” Needed

- Electrical/Electronic devices are increasingly being used in applications where reliable functionality is required
- At the same time, the electromagnetic environment is increasing to higher levels of ambient noise

Functional Safety

- EMI is controlled by the EMC Directive
 - Does not address safety
 - EMC engineers generally do not have a detailed knowledge of safety
- Low Voltage Directive do not address EMC very well if at all
 - Safety engineers generally do not have a detailed knowledge of EMC

Standards

- There are no EMC standards that are suited for achieving functional safety
- There are no safety standards that are suited for EMC functional safety
- IEC 61508
 - Covers EMI functional safety, but offers no specifics
 - Is not a listed under any EU directive
 - IEC 61511 / IEC 62061
- IEC TS 61000-1-2
 - Offers practical recommendations

Shortcomings of Existing Immunity

- Faults and misuse are not addressed
- Real environments are not addressed
- No EMI risk assessment is done
- Physical environment is not considered
- Complex interactions are not considered
- Shortcomings of “Performance Criteria”
- Process applies to entire lifecycle

Examples

- Functional EMC is a system issue and cannot be fashioned by simply combining the reliable items
 - Example
 - Closed loop speed sensor
 - Analog sensor with a magnetic coil sensing a magnetic
 - Comparator to convert “analog” to digital
 - Microprocessor to control speed
 - For high speed, higher rates of pulses and less impact from noise
 - For low speed, lower rate of pulses and more impact from noise
 - Unreliability could be very high at low speeds
 - Pacemaker

Examples

- Example of environment change
 - In the 1990's analog cellphones were being replaced by digital cellphones. The digital cellphones operated at the same carrier frequency (around 900 MHz) as the analog cellphone, and operated at about the same power level. However, where the analog cellphones did not cause interference to hearing aids, the digital ones did. The difference, and what caused the interference, was the change to digital modulation.

The Consultant's Oath

If you're not a part of the solution,
there's good money to be made in
prolonging the problem.

EMC Functional Safety Process

- Planning
 - Management Responsibilities
 - Procedures
 - Department interfaces and responsibilities
 - Authority
 - Supplier responsibilities
 - Budget and schedule
 - Develop an EMC Safety Plan
 - Location / environment / lifecycle
 - What standards or specifications
 - Design guides / training / consulting / testing / documentation

Step 1: Determine the environment

- Determine the worst-case electromagnetic environment that the device could reasonably be exposed to over its expected lifecycle
 - Mobile and portable devices
 - Future technology trends
 - Take into account “uncertainties”
 - EM threats caused by foreseeable misuse
 - Simultaneous threats
 - Effects of transport and storage
 - Use of existing IEC standards (61000-2-5)
 - If unknown, then make an “educated” guess

Step 1: Determine the environment (cont)

- Physical environment
 - Could affect filtering, shielding, etc.
 - Liquids, molding, sand, dust, cleaning
 - Maintenance
 - Opening / closing panels and doors
 - Extended operations of controls
- Perform a site survey

Step 2: Determine intrasystem environment

- Determine the worst-case electromagnetic environment that the device could reasonably be exposed from other parts of itself
 - Drifting of parameters
 - Aging of components or materials
 - Effect of external environment such as vibration, temperature, humidity, etc.
 - Corrosion
 - Take into account “uncertainties”
 - Effects of transport and storage

Step 3: Specify EM vs functional performance

- Hazard identification
- Uncertainties
- Risk Analysis = Severity * Probability
 - Initial / Final
 - FMEA (MIL-STD-1629)
 - Criticality Analysis (FMECA)
 - MIL-HDBK-217 Reliability Standard
 - Event Tree
 - Fault Tree
 - Worst-case Analysis

Step 4: Study and Design

- Designing the device to achieve the required level of safety risk or risk reduction
 - Chose suitable hardware and software
 - Communication techniques
 - Detection techniques
 - Correction techniques
 - Optical
 - Use of appropriate design guides and techniques
 - Shielding / separation
 - Filtering
 - PCB design
 - Power distribution
 - Simulation tools

Step 4: Study and Design (cont.)

- Use of appropriate design guides and techniques
 - Physical techniques (e.g. ventilation, sealing, vibration, thermal, oxidation, etc.)
 - Safety engineering techniques
 - Fuses
 - Effects of component short/open
 - Overvoltage / overcurrent protection
 - Control of suppliers and subcontractors
 - Ensure correct operation, maintenance, repair, and refurbishment
 - Good instructions

Step 4: Study and Design (cont.)

- Overcome lack of useful product data
 - Protective enclosure
 - Clever design
 - Additional product testing
 - Use a custom product

Step 4: Study and Design (cont.)

- This is an iterative process since any new design or marketing changes should be re-assessed (i.e. it's a living document)
- Do not consider only single fault
 - 10 independent faults that each occurs every 100 years for a particular hazard, so this hazard could occur in 10 years – may still unacceptable!

Step 5: Create a Verification/Validation Plan

- EMC Testing
- Expert Review
 - Checklists
 - Inspections
 - Reviews
 - Audits
- Non-standardized testing
- Modelling / analysis
- HALT / HAAS

FIRST EXAMPLE HAZARD RISK ASSESSMENT MATRIX

HAZARD CATEGORY	(1) CATASTROPHIC	(2) CRITICAL	(3) MARGINAL	(4) NEGLIGIBLE
FREQUENCY				
(A) FREQUENT ($X > 10^{-1}$) ^a	1A	2A	3A	4A
(B) PROBABLE ($10^{-1} > X > 10^{-2}$) ^a	1B	2B	3B	4B
(C) OCCASIONAL ($10^{-2} > X > 10^{-3}$) ^a	1C	2C	3C	4C
(D) REMOTE ($10^{-3} > X > 10^{-6}$) ^a	1D	2D	3D	4D
(E) IMPROBABLE ($10^{-6} > X$) ^a	1E	2E	3E	4E

* Example of quantitative criteria

Hazard Risk Index

1A, 1B, 1C, 2A, 2B, 3A
1D, 2C, 2D, 3B, 3C
1E, 2E, 3D, 3E, 4A, 4B
4C, 4D, 4E

Suggested Criteria

Unacceptable
Undesirable (MA decision required)
Acceptable with review by MA
Acceptable without review

EXAMPLE DECISION AUTHORITY MATRIX FOR RESIDUAL RISK

HAZARD CATEGORY	CATASTROPHIC	CRITICAL	MARGINAL	NEGLIGIBLE
FREQUENCY				
FREQUENT	HIGH	HIGH	HIGH	MEDIUM
PROBABLE	HIGH	HIGH	MEDIUM	LOW
OCCASIONAL	HIGH	HIGH	MEDIUM	LOW
REMOTE	HIGH	MEDIUM	LOW	LOW
IMPROBABLE	MEDIUM	LOW	LOW	LOW

Hazard Risk Level

HIGH
MEDIUM
LOW

Decision Authority

Service Acquisition Executive
Program Executive Officer
Program Manager

Probability	Severity				
	e	d	c	b	a
E	4	4	4	3	3
D	4	4	3	3	2
C	4	4	3	2	1
B	3	4	2	1	1
A	3	2	1	1	1

Interpretation of Risk Index

Risk Index	Interpretation
4	Acceptable only if approved by company management
3	Acceptable if approved by project management
2	Acceptable with design review
1	Acceptable as implemented

Definitions of Probabilities:

- E:** Frequent - Likely to occur many times per year for each system (e.g., untrained operator errors)
- D:** Probable - Likely to occur only a few times per year for each system (e.g., trained operator errors)
- C:** Occasional - Likely to occur less than once every year for each system (e.g., failures of consumable accessories)
- B:** Remote - Likely to occur less than once in the life of the system (e.g., electromechanical failures)
- A:** Extremely Unlikely - Never expected to occur in the life of the system (e.g., semiconductor or passive electronics failures)

Definitions of Severity:

- e:** Catastrophic: May result in death to a typical operator or patient.
- d:** Critical: May result in major injury (requiring physician intervention or therapy) to a typical patient or operator.
- c:** Marginal: May result in minor injury a typical patient or operator (does not require physician intervention).
- b:** Moderate: May result in damage to the system (placing the device out of service), but no injury to a typical patient or operator.
- a:** Negligible: May cause minor nuisance to the operator or patient, but no injury or system damage.

SYSTEM: ██████████
 SUBSYSTEM: ██████████
 Ref. Dwg.: ██████████

FMEA WORKSHEET

DATE: ██████████
 SHEET 5 OF 25
 COMPILED BY: ██████████

ID #	DESIG	FUNCTION	FAILURE MODE	SUBSYSTEM EFFECT	SYSTEM EFFECT	FAILURE DETECTION	HAZARD CATEGORY	REMARKS
1031	U1-32	MTRAØ4	OPEN =ØV =5V	ERRATIC MOTOR	OCCCLUSION	SA	CAT II	—
1032	U1-33	SLIDE CLAMP A DETECTION	OPEN =ØV =5V	ERRONEOUS SC SIGNAL	HIE=	SA; SELF TEST FAIL	CAT II	TEST TEST TEST
1033	U1-34	MTRBØ3	OPEN =ØV =5V	ERRATIC MOTOR	OCCCLUSION	SA	CAT II	—
1034	U1-35	MTRBØ4	OPEN =ØV =5V	ERRATIC MOTOR	OCCCLUSION	SA	CAT II	—
1035	U1-36	VSS SUBSTRATE POWER	OPEN	PFE	PS; AA	WATCHDOG	CAT II	TEST
1036	U1-37	VPP PROGRAM POWER	OPEN	MAY BE NONE	NOISE ?	NONE ?	?	TEST
1037	U1-38	MTR B HIGH CURRENT	OPEN =ØV =5V	HOLDING ONLY CURRENT ALWAYS ON	OCCCLUSION WASTED PWR	SA NONE ?		— — —
1038	U1-39	POWER OFF Z	OPEN =ØV =5V	POSSIBLE TURN OFF PUMP OFF PUMP CAN'T TURN OFF	PUMP OFF, AA PUMP OFF, AA	HARDWARE-UZ HARDWARE-UZ OPERATOR	CAT II CAT II CAT II	— TEST TEST - Try TURN OFF

SYSTEM: [REDACTED]
 SUBSYSTEM: [REDACTED]
 REF DWG: [REDACTED]

FMEA CRITICALITY

DATE: [REDACTED]
 SHEET 26 OF 74
 COMPILED BY: [REDACTED]

ID #	DESIG	FUNCTION	FAILURE MODE	SYSTEM EFFECT	FAILURE PROBABILITY	SEVERITY	FMEA CRITICALITY
100	NONE	POWER CORD	OPEN GROUND	NO GROUND	0.005	1	0.005
101	NONE	GROUND WIRE	OPEN SOLDER JOINT	NO GROUND	0.004	1	0.004
175	U2	EPROM	BIT ERROR	PROGRAM ERROR	6.00E-04	4	0.0024
185	LED 2	DISPLAY	MISSING SEGMENT	DISPLAY ERROR	0.001	3	0.003

Conclusion

- Functional safety requires much more than simply asking a test laboratory to perform some standardized tests
- Achieve a required level of confidence in functional safety performance over the anticipated lifetime